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| Search Notes  | Application/Control No. 10653021 | Applicant(s)/Patent Under Reexamination LUO ET AL. |
| | Examiner Chawan, Sheela C | Art Unit 2624 |

| SEARCHED | | | |
|-----------------------------|--|---------|----------|
| Class | Subclass | Date | Examiner |
| 382 | 117,167,165,275,164,103,274,118,199,173,162,190,115, | 1/22/07 | SCC |
| 348 | 239,241, | " | " |
| 396 | 191,198, | " | " |
| 426 | 72,311,620,640,641,658 | " | " |
| 382 | 117,274 | 7/16/08 | SCC |
| ABOVE SEARCH UP- DATE | | 7/16/08 | SCC |

| SEARCH NOTES | | |
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| Search Notes | Date | Examiner |
| EAST,US-PGPUB,USPAT,EPO,JPO,DERWENT, IBM-TDB. | 1/22/07 | SCC |
| INVENTOR NAME SEARCH. | " | " |
| SEARCH EAST AND OTHER DATABASE, SEE THE SEARCH HISTORY | 7/16/08 | SCC |
| 382/117,275,274,118, CCLS. SEARCH US-PATENT TEXT SEARCH ONLY. | 7/16/08 | SCC |
| INTERFERENCE SEARCH | 7/16/08 | SCC |
| SEARCH IEEE OR INSPEC DATA BASE. | 7/16/08 | SCC |

| INTERFERENCE SEARCH | | | |
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| Class | Subclass | Date | Examiner |
| 382 | 117, 274 | 7/16/08 | SCC |